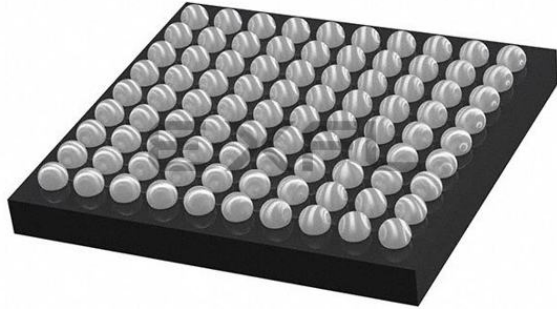


Welcome to [E-XFL.COM](http://E-XFL.COM)

### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"



#### Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	168MHz
Connectivity	CANbus, EBI/EMI, I <sup>2</sup> C, IrDA, LINbus, SPI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, I <sup>2</sup> S, LCD, POR, PWM, WDT
Number of I/O	72
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	192K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 13x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	90-UFBGA, WLCSP
Supplier Device Package	90-WLCSP (4.22x3.97)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f415ogy6tr">https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f415ogy6tr</a>

- 8- to 14-bit parallel camera interface up to 54 Mbytes/s
- Cryptographic acceleration: hardware acceleration for AES 128, 192, 256, Triple DES, HASH (MD5, SHA-1), and HMAC
- True random number generator
- CRC calculation unit
- 96-bit unique ID
- RTC: subsecond accuracy, hardware calendar

**Table 1. Device summary**

Reference	Part number
STM32F415xx	STM32F415RG, STM32F415VG, STM32F415ZG, STM32F415OG
STM32F417xx	STM32F417VG, STM32F417IG, STM32F417ZG, STM32F417VE, STM32F417ZE, STM32F417IE

## List of tables

Table 1.	Device summary . . . . .	2
Table 2.	STM32F415xx and STM32F417xx: features and peripheral counts. . . . .	15
Table 3.	Regulator ON/OFF and internal reset ON/OFF availability. . . . .	31
Table 4.	Timer feature comparison. . . . .	33
Table 5.	USART feature comparison . . . . .	37
Table 6.	Legend/abbreviations used in the pinout table . . . . .	49
Table 7.	STM32F41xxx pin and ball definitions . . . . .	50
Table 8.	FSMC pin definition . . . . .	62
Table 9.	Alternate function mapping . . . . .	65
Table 10.	STM32F41x register boundary addresses . . . . .	75
Table 11.	Voltage characteristics . . . . .	81
Table 12.	Current characteristics . . . . .	82
Table 13.	Thermal characteristics. . . . .	82
Table 14.	General operating conditions . . . . .	82
Table 15.	Limitations depending on the operating power supply range . . . . .	84
Table 16.	VCAP_1/VCAP_2 operating conditions . . . . .	85
Table 17.	Operating conditions at power-up / power-down (regulator ON) . . . . .	85
Table 18.	Operating conditions at power-up / power-down (regulator OFF). . . . .	85
Table 19.	Embedded reset and power control block characteristics. . . . .	86
Table 20.	Typical and maximum current consumption in Run mode, code with data processing running from Flash memory (ART accelerator enabled) or RAM . . . . .	88
Table 21.	Typical and maximum current consumption in Run mode, code with data processing running from Flash memory (ART accelerator disabled) . . . . .	89
Table 22.	Typical and maximum current consumption in Sleep mode . . . . .	92
Table 23.	Typical and maximum current consumptions in Stop mode . . . . .	93
Table 24.	Typical and maximum current consumptions in Standby mode . . . . .	93
Table 25.	Typical and maximum current consumptions in V <sub>BAT</sub> mode. . . . .	94
Table 26.	Typical current consumption in Run mode, code with data processing running from Flash memory, regulator ON (ART accelerator enabled except prefetch), V <sub>DD</sub> = 1.8 V. . . . .	96
Table 27.	Switching output I/O current consumption . . . . .	98
Table 28.	Peripheral current consumption . . . . .	99
Table 29.	Low-power mode wakeup timings . . . . .	103
Table 30.	High-speed external user clock characteristics. . . . .	103
Table 31.	Low-speed external user clock characteristics . . . . .	104
Table 32.	HSE 4-26 MHz oscillator characteristics . . . . .	105
Table 33.	LSE oscillator characteristics (f <sub>LSE</sub> = 32.768 kHz) . . . . .	106
Table 34.	HSI oscillator characteristics . . . . .	107
Table 35.	LSI oscillator characteristics . . . . .	107
Table 36.	Main PLL characteristics. . . . .	108
Table 37.	PLLI2S (audio PLL) characteristics . . . . .	109
Table 38.	SSCG parameters constraint . . . . .	110
Table 39.	Flash memory characteristics . . . . .	112
Table 40.	Flash memory programming. . . . .	112
Table 41.	Flash memory programming with VPP . . . . .	114
Table 42.	Flash memory endurance and data retention. . . . .	114
Table 43.	EMS characteristics . . . . .	115
Table 44.	EMI characteristics . . . . .	116

## 2 Description

The STM32F415xx and STM32F417xx family is based on the high-performance ARM<sup>®</sup> Cortex<sup>®</sup>-M4 32-bit RISC core operating at a frequency of up to 168 MHz. The Cortex-M4 core features a Floating point unit (FPU) single precision which supports all ARM single-precision data-processing instructions and data types. It also implements a full set of DSP instructions and a memory protection unit (MPU) which enhances application security.

The STM32F415xx and STM32F417xx family incorporates high-speed embedded memories (Flash memory up to 1 Mbyte, up to 192 Kbytes of SRAM), up to 4 Kbytes of backup SRAM, and an extensive range of enhanced I/Os and peripherals connected to two APB buses, three AHB buses and a 32-bit multi-AHB bus matrix.

All devices offer three 12-bit ADCs, two DACs, a low-power RTC, twelve general-purpose 16-bit timers including two PWM timers for motor control, two general-purpose 32-bit timers, a true random number generator (RNG), and a cryptographic acceleration cell. They also feature standard and advanced communication interfaces.

- Up to three I<sup>2</sup>Cs
- Three SPIs, two I<sup>2</sup>Ss full duplex. To achieve audio class accuracy, the I2S peripherals can be clocked via a dedicated internal audio PLL or via an external clock to allow synchronization.
- Four USARTs plus two UARTs
- An USB OTG full-speed and a USB OTG high-speed with full-speed capability (with the ULPI),
- Two CANs
- An SDIO/MMC interface
- Ethernet and the camera interface available on STM32F417xx devices only.

New advanced peripherals include an SDIO, an enhanced flexible static memory control (FSMC) interface (for devices offered in packages of 100 pins and more), a camera interface for CMOS sensors and a cryptographic acceleration cell. Refer to [Table 2: STM32F415xx and STM32F417xx: features and peripheral counts](#) for the list of peripherals available on each part number.

The STM32F415xx and STM32F417xx family operates in the –40 to +105 °C temperature range from a 1.8 to 3.6 V power supply. The supply voltage can drop to 1.7 V when the device operates in the 0 to 70 °C temperature range using an external power supply supervisor: refer to [Section : Internal reset OFF](#). A comprehensive set of power-saving mode allows the design of low-power applications.

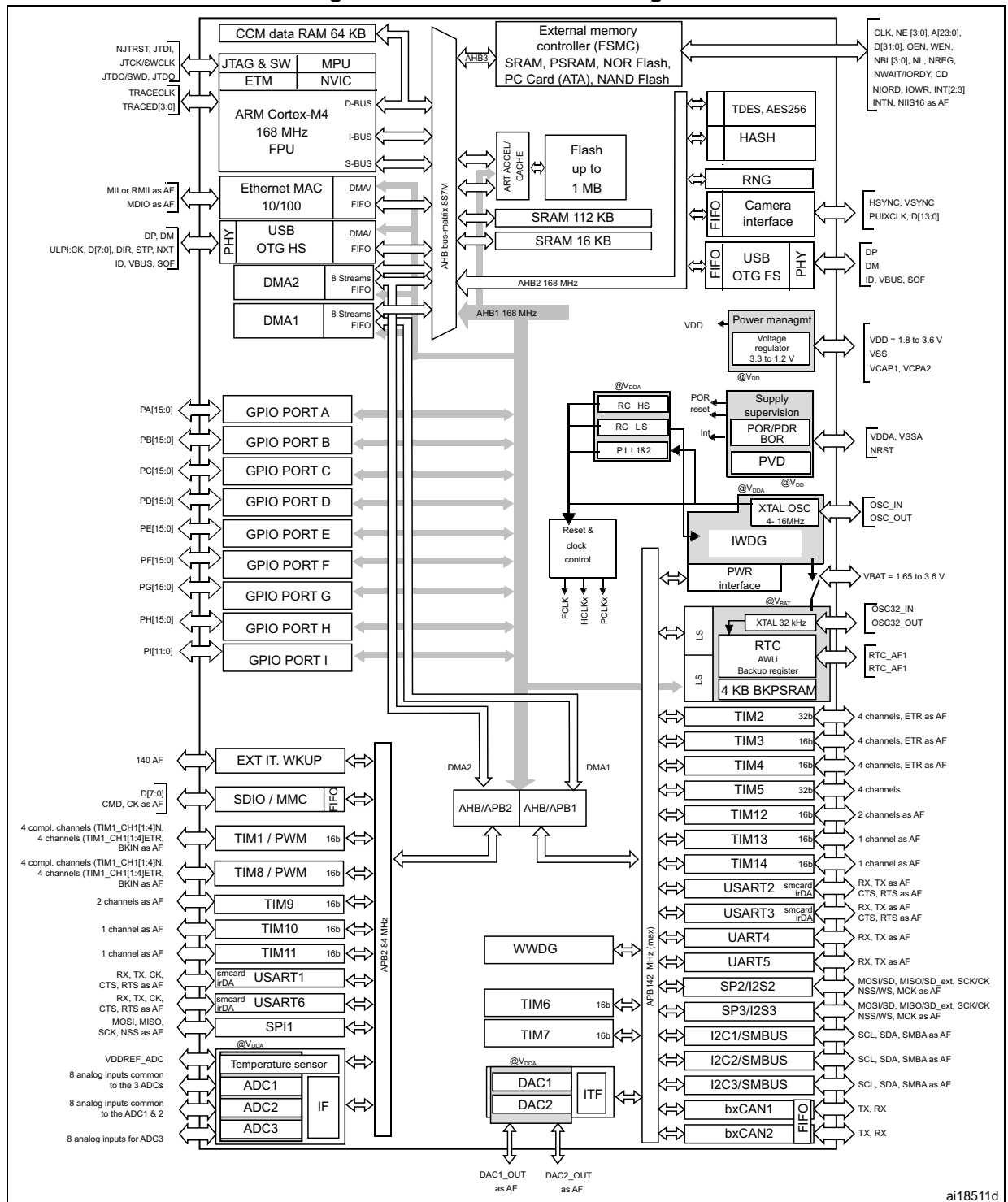
The STM32F415xx and STM32F417xx family offers devices in various packages ranging from 64 pins to 176 pins. The set of included peripherals changes with the device chosen.

These features make the STM32F415xx and STM32F417xx microcontroller family suitable for a wide range of applications:

- Motor drive and application control
- Medical equipment
- Industrial applications: PLC, inverters, circuit breakers
- Printers, and scanners
- Alarm systems, video intercom, and HVAC
- Home audio appliances

## 2.2 Device overview

Figure 5. STM32F41xxx block diagram



1. The camera interface and ethernet are available only on STM32F417xx devices.

Figure 17. STM32F41xxx WLCSP90 ballout

	10	9	8	7	6	5	4	3	2	1
A	VBAT	PC13	PDR_ON	BOOT0	PB4	PD7	PD4	PC12	PA14	VDD
B	PC14	PC15	VDD	PB7	PB3	PD6	PD2	PA15	PI1	VCAP_2
C	PA0	VSS	PB9	PB6	PD5	PD1	PC11	PI0	PA12	PA11
D	PC2	BYPASS_REG	PB8	PB5	PD0	PC10	PA13	PA10	PA9	PA8
E	PC0	PC3	VSS	VSS	VDD	VSS	VDD	PC9	PC8	PC7
F	PH0	PH1	PA1	VDD	PE10	PE14	VCAP_1	PC6	PD14	PD15
G	NRST	VDDA	PA5	PB0	PE7	PE13	PE15	PD10	PD12	PD11
H	VSSA	PA3	PA6	PB1	PE8	PE12	PB10	PD9	PD8	PB15
J	PA2	PA4	PA7	PB2	PE9	PE11	PB11	PB12	PB14	PB13

MS30402V1

1. This figure shows the package bump view.

Table 6. Legend/abbreviations used in the pinout table

Name	Abbreviation	Definition
Pin name		Unless otherwise specified in brackets below the pin name, the pin function during and after reset is the same as the actual pin name
Pin type	S	Supply pin
	I	Input only pin
	I/O	Input / output pin
I/O structure	FT	5 V tolerant I/O
	TTa	3.3 V tolerant I/O directly connected to ADC
	B	Dedicated BOOT0 pin
	RST	Bidirectional reset pin with embedded weak pull-up resistor
Notes		Unless otherwise specified by a note, all I/Os are set as floating inputs during and after reset
Alternate functions		Functions selected through GPIOx_AFR registers
Additional functions		Functions directly selected/enabled through peripheral registers

Table 7. STM32F41xxx pin and ball definitions (continued)

Pin number						Pin name (function after reset) <sup>(1)</sup>	Pin type	I/O structure	Notes	Alternate functions	Additional functions
LQFP64	WLCSP90	LQFP100	LQFP144	UFBGA176	LQFP176						
40	E3	66	99	F14	118	PC9	I/O	FT	-	I2S_CKIN/ MCO2 / TIM8_CH4/SDIO_D1 / /I2C3_SDA / DCMI_D3 / TIM3_CH4/ EVENTOUT	-
41	D1	67	100	F15	119	PA8	I/O	FT	-	MCO1 / USART1_CK/ TIM1_CH1/ I2C3_SCL/ OTG_FS_SOF/ EVENTOUT	-
42	D2	68	101	E15	120	PA9	I/O	FT	-	USART1_TX/ TIM1_CH2 / I2C3_SMBA / DCMI_D0/ EVENTOUT	OTG_FS_VBUS
43	D3	69	102	D15	121	PA10	I/O	FT	-	USART1_RX/ TIM1_CH3/ OTG_FS_ID/DCMI_D1/ EVENTOUT	-
44	C1	70	103	C15	122	PA11	I/O	FT	-	USART1_CTS / CAN1_RX / TIM1_CH4 / OTG_FS_DM/ EVENTOUT	-
45	C2	71	104	B15	123	PA12	I/O	FT	-	USART1_RTS / CAN1_TX/ TIM1_ETR/ OTG_FS_DP/ EVENTOUT	-
46	D4	72	105	A15	124	PA13 (JTMS-SWDIO)	I/O	FT	-	JTMS-SWDIO/ EVENTOUT	-
47	B1	73	106	F13	125	V <sub>CAP_2</sub>	S	-	-	-	-
-	E7	74	107	F12	126	V <sub>SS</sub>	S	-	-	-	-
48	E6	75	108	G13	127	V <sub>DD</sub>	S	-	-	-	-
-	-	-	-	E12	128	PH13	I/O	FT	-	TIM8_CH1N / CAN1_TX/ EVENTOUT	-
-	-	-	-	E13	129	PH14	I/O	FT	-	TIM8_CH2N / DCMI_D4/ EVENTOUT	-
-	-	-	-	D13	130	PH15	I/O	FT	-	TIM8_CH3N / DCMI_D11/ EVENTOUT	-
-	C3	-	-	E14	131	PI0	I/O	FT	-	TIM5_CH4 / SPI2_NSS / I2S2_WS / DCMI_D13/ EVENTOUT	-
-	B2	-	-	D14	132	PI1	I/O	FT	-	SPI2_SCK / I2S2_CK / DCMI_D8/ EVENTOUT	-

Table 10. STM32F41x register boundary addresses (continued)

Bus	Boundary address	Peripheral	
AHB1	0x4004 0000 - 0x4007 FFFF	USB OTG HS	
	0x4002 9400 - 0x4003 FFFF	Reserved	
	0x4002 9000 - 0x4002 93FF	ETHERNET MAC	
	0x4002 8C00 - 0x4002 8FFF		
	0x4002 8800 - 0x4002 8BFF		
	0x4002 8400 - 0x4002 87FF		
	0x4002 8000 - 0x4002 83FF		
	0x4002 6800 - 0x4002 7FFF	Reserved	
	0x4002 6400 - 0x4002 67FF	DMA2	
	0x4002 6000 - 0x4002 63FF	DMA1	
	0x4002 5000 - 0x4002 5FFF	Reserved	
	0x4002 4000 - 0x4002 4FFF	BKPSRAM	
	0x4002 3C00 - 0x4002 3FFF	Flash interface register	
	0x4002 3800 - 0x4002 3BFF	RCC	
	0x4002 3400 - 0x4002 37FF	Reserved	
	0x4002 3000 - 0x4002 33FF	CRC	
	0x4002 2400 - 0x4002 2FFF	Reserved	
	0x4002 2000 - 0x4002 23FF	GPIOI	
	0x4002 1C00 - 0x4002 1FFF	GPIOH	
	0x4002 1800 - 0x4002 1BFF	GPIOG	
	0x4002 1400 - 0x4002 17FF	GPIOF	
	0x4002 1000 - 0x4002 13FF	GPIOE	
	0x4002 0C00 - 0x4002 0FFF	GIOD	
	0x4002 0800 - 0x4002 0BFF	GPIOC	
	0x4002 0400 - 0x4002 07FF	GPIOB	
	0x4002 0000 - 0x4002 03FF	GPIOA	
		0x4001 5800- 0x4001 FFFF	Reserved



**Table 19. Embedded reset and power control block characteristics (continued)**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{BOR2}$	Brownout level 2 threshold	Falling edge	2.44	2.50	2.56	V
		Rising edge	2.53	2.59	2.63	V
$V_{BOR3}$	Brownout level 3 threshold	Falling edge	2.75	2.83	2.88	V
		Rising edge	2.85	2.92	2.97	V
$V_{BORhyst}^{(1)}$	BOR hysteresis	-	-	100	-	mV
$T_{RSTTEMPO}^{(1)(2)}$	Reset temporization	-	0.5	1.5	3.0	ms
$I_{RUSH}^{(1)}$	InRush current on voltage regulator power-on (POR or wakeup from Standby)	-	-	160	200	mA
$E_{RUSH}^{(1)}$	InRush energy on voltage regulator power-on (POR or wakeup from Standby)	$V_{DD} = 1.8\text{ V}$ , $T_A = 105\text{ }^\circ\text{C}$ , $I_{RUSH} = 171\text{ mA}$ for $31\text{ }\mu\text{s}$	-	-	5.4	$\mu\text{C}$

1. Guaranteed by design.

2. The reset temporization is measured from the power-on (POR reset or wakeup from  $V_{BAT}$ ) to the instant when first instruction is read by the user application code.

### 5.3.6 Supply current characteristics

The current consumption is a function of several parameters and factors such as the operating voltage, ambient temperature, I/O pin loading, device software configuration, operating frequencies, I/O pin switching rate, program location in memory and executed binary code.

The current consumption is measured as described in [Figure 22: Current consumption measurement scheme](#).

All Run mode current consumption measurements given in this section are performed using a CoreMark-compliant code.

#### Typical and maximum current consumption

The MCU is placed under the following conditions:

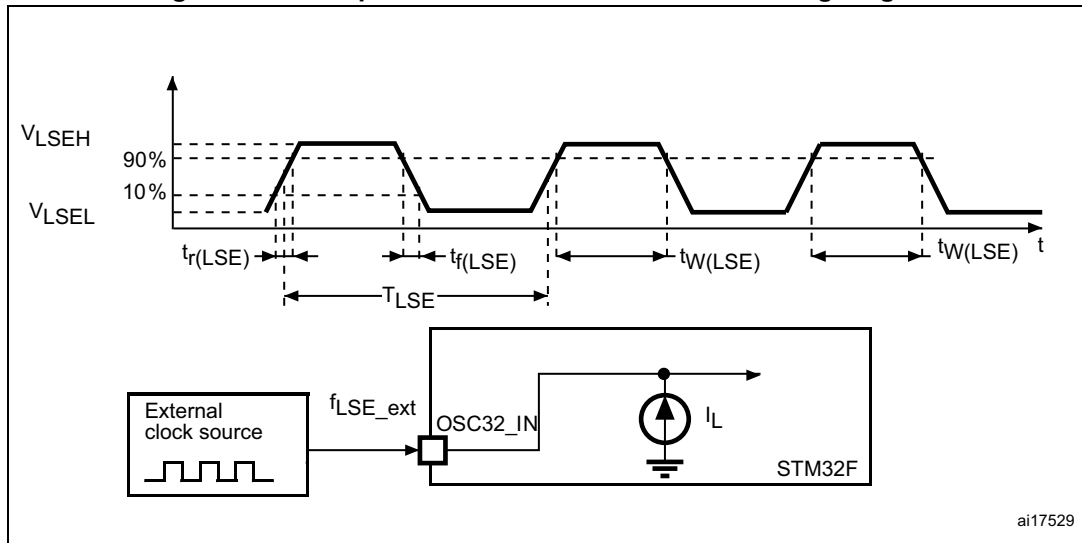
- At startup, all I/O pins are configured as analog inputs by firmware.
- All peripherals are disabled except if it is explicitly mentioned.
- The Flash memory access time is adjusted to  $f_{HCLK}$  frequency (0 wait state from 0 to 30 MHz, 1 wait state from 30 to 60 MHz, 2 wait states from 60 to 90 MHz, 3 wait states from 90 to 120 MHz, 4 wait states from 120 to 150 MHz, and 5 wait states from 150 to 168 MHz).
- When the peripherals are enabled HCLK is the system clock,  $f_{PCLK1} = f_{HCLK}/4$ , and  $f_{PCLK2} = f_{HCLK}/2$ , except is explicitly mentioned.
- The maximum values are obtained for  $V_{DD} = 3.6\text{ V}$  and maximum ambient temperature ( $T_A$ ), and the typical values for  $T_A = 25\text{ }^\circ\text{C}$  and  $V_{DD} = 3.3\text{ V}$  unless otherwise specified.

Table 22. Typical and maximum current consumption in Sleep mode

Symbol	Parameter	Conditions	f <sub>HCLK</sub>	Typ	Max <sup>(1)</sup>		Unit
				T <sub>A</sub> = 25 °C	T <sub>A</sub> = 85 °C	T <sub>A</sub> = 105 °C	
I <sub>DD</sub>	Supply current in Sleep mode	External clock <sup>(2)</sup> , all peripherals enabled <sup>(3)</sup>	168 MHz	59	77	84	mA
			144 MHz	46	61	67	
			120 MHz	38	53	60	
			90 MHz	30	44	51	
			60 MHz	20	34	41	
			30 MHz	11	24	31	
			25 MHz	8	21	28	
			16 MHz	6	18	25	
			8 MHz	3	16	23	
			4 MHz	2	15	22	
		2 MHz	2	14	21		
		External clock <sup>(2)</sup> , all peripherals disabled	168 MHz	12	27	35	
			144 MHz	9	22	29	
			120 MHz	8	20	28	
			90 MHz	7	19	26	
			60 MHz	5	17	24	
			30 MHz	3	16	23	
			25 MHz	2	15	22	
			16 MHz	2	14	21	
			8 MHz	1	14	21	
4 MHz	1		13	21			
2 MHz	1	13	21				

1. Guaranteed by characterization, tested in production at V<sub>DD</sub> max and f<sub>HCLK</sub> max with peripherals enabled.
2. External clock is 4 MHz and PLL is on when f<sub>HCLK</sub> > 25 MHz.
3. Add an additional power consumption of 1.6 mA per ADC for the analog part. In applications, this consumption occurs only while the ADC is ON (ADON bit is set in the ADC\_CR2 register).

Figure 31. Low-speed external clock source AC timing diagram



**High-speed external clock generated from a crystal/ceramic resonator**

The high-speed external (HSE) clock can be supplied with a 4 to 26 MHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in [Table 32](#). In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

Table 32. HSE 4-26 MHz oscillator characteristics <sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f <sub>OSC_IN</sub>	Oscillator frequency	-	4	-	26	MHz
R <sub>F</sub>	Feedback resistor	-	-	200	-	kΩ
G <sub>m</sub>	Oscillator transconductance	Startup	5	-	-	mA/V
G <sub>mcritmax</sub>	Maximum critical crystal G <sub>m</sub>		-	-	1	
t <sub>SU(HSE)</sub> <sup>(2)</sup>	Startup time	V <sub>DD</sub> is stabilized	-	2	-	ms

1. Guaranteed by design.
2. Guaranteed by characterization. t<sub>SU(HSE)</sub> is the startup time measured from the moment it is enabled (by software) to a stabilized 8 MHz oscillation is reached. This value is measured for a standard crystal resonator and can vary significantly with the crystal manufacturer

For C<sub>L1</sub> and C<sub>L2</sub>, it is recommended to use high-quality external ceramic capacitors in the 5 pF to 25 pF range (typ.), designed for high-frequency applications, and selected to match the requirements of the crystal or resonator (see [Figure 32](#)). C<sub>L1</sub> and C<sub>L2</sub> are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of C<sub>L1</sub> and C<sub>L2</sub>. PCB and MCU pin capacitance must be included (10 pF can be used as a rough estimate of the combined pin and board capacitance) when sizing C<sub>L1</sub> and C<sub>L2</sub>.

**Table 36. Main PLL characteristics (continued)**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
Jitter <sup>(3)</sup>	Cycle-to-cycle jitter	System clock 120 MHz	RMS	-	25	-	ps
			peak to peak	-	±150	-	
	Period Jitter		RMS	-	15	-	
			peak to peak	-	±200	-	
	Main clock output (MCO) for RMI Ethernet	Cycle to cycle at 50 MHz on 1000 samples	-	32	-		
	Main clock output (MCO) for MII Ethernet	Cycle to cycle at 25 MHz on 1000 samples	-	40	-		
	Bit Time CAN jitter	Cycle to cycle at 1 MHz on 1000 samples	-	330	-		
I <sub>DD(PLL)</sub> <sup>(4)</sup>	PLL power consumption on VDD	VCO freq = 100 MHz VCO freq = 432 MHz	0.15 0.45	-	0.40 0.75	mA	
I <sub>DDA(PLL)</sub> <sup>(4)</sup>	PLL power consumption on VDDA	VCO freq = 100 MHz VCO freq = 432 MHz	0.30 0.55	-	0.40 0.85	mA	

1. Take care of using the appropriate division factor M to obtain the specified PLL input clock values. The M factor is shared between PLL and PLLI2S.
2. Guaranteed by design.
3. The use of 2 PLLs in parallel could degraded the Jitter up to +30%.
4. Guaranteed by characterization.

**Table 37. PLLI2S (audio PLL) characteristics**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
f <sub>PLLI2S_IN</sub>	PLLI2S input clock <sup>(1)</sup>	-	0.95 <sup>(2)</sup>	1	2.10	MHz	
f <sub>PLLI2S_OUT</sub>	PLLI2S multiplier output clock	-	-	-	216	MHz	
f <sub>VCO_OUT</sub>	PLLI2S VCO output	-	100	-	432	MHz	
t <sub>LOCK</sub>	PLLI2S lock time	VCO freq = 100 MHz	75	-	200	µs	
		VCO freq = 432 MHz	100	-	300		
Jitter <sup>(3)</sup>	Master I <sup>2</sup> S clock jitter	Cycle to cycle at 12.288 MHz on 48KHz period, N=432, R=5	RMS	-	90	-	ps
			peak to peak	-	±280	-	
		Average frequency of 12.288 MHz N = 432, R = 5 on 1000 samples	-	90	-	ps	
	WS I <sup>2</sup> S clock jitter	Cycle to cycle at 48 KHz on 1000 samples	-	400	-	ps	

Table 50. I/O AC characteristics<sup>(1)(2)</sup> (continued)

OSPEEDRy [1:0] bit value <sup>(1)</sup>	Symbol	Parameter	Conditions	Min	Typ	Max	Unit
11	F <sub>max(IO)out</sub>	Maximum frequency <sup>(3)</sup>	C <sub>L</sub> = 30 pF, V <sub>DD</sub> > 2.70 V	-	-	100 <sup>(4)</sup>	MHz
			C <sub>L</sub> = 30 pF, V <sub>DD</sub> > 1.8 V	-	-	50 <sup>(4)</sup>	
			C <sub>L</sub> = 10 pF, V <sub>DD</sub> > 2.70 V	-	-	180 <sup>(4)</sup>	
			C <sub>L</sub> = 10 pF, V <sub>DD</sub> > 1.8 V	-	-	100 <sup>(4)</sup>	
	t <sub>f(IO)out</sub> / t <sub>r(IO)out</sub>	Output high to low level fall time and output low to high level rise time	C <sub>L</sub> = 30 pF, V <sub>DD</sub> > 2.70 V	-	-	4	ns
			C <sub>L</sub> = 30 pF, V <sub>DD</sub> > 1.8 V	-	-	6	
			C <sub>L</sub> = 10 pF, V <sub>DD</sub> > 2.70 V	-	-	2.5	
			C <sub>L</sub> = 10 pF, V <sub>DD</sub> > 1.8 V	-	-	4	
-	t <sub>EXTIpw</sub>	Pulse width of external signals detected by the EXTI controller		10	-	-	ns

1. Guaranteed by characterization.
2. The I/O speed is configured using the OSPEEDRy[1:0] bits. Refer to the STM32F4xx reference manual for a description of the GPIOx\_SPEEDR GPIO port output speed register.
3. The maximum frequency is defined in [Figure 37](#).
4. For maximum frequencies above 50 MHz, the compensation cell should be used.

Figure 37. I/O AC characteristics definition

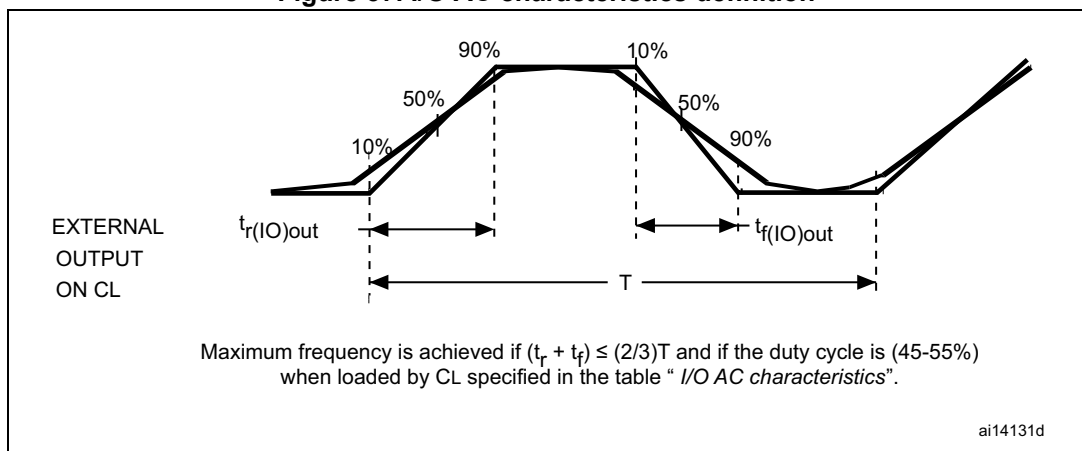


Table 81. Synchronous non-multiplexed NOR/PSRAM read timings<sup>(1)(2)</sup>

Symbol	Parameter	Min	Max	Unit
$t_{w(\text{CLK})}$	FSMC_CLK period	$2T_{\text{HCLK}} - 0.5$	-	ns
$t_{d(\text{CLKL-NExL})}$	FSMC_CLK low to FSMC_NEx low (x=0..2)	-	0.5	ns
$t_{d(\text{CLKL-NExH})}$	FSMC_CLK low to FSMC_NEx high (x= 0..2)	0	-	ns
$t_{d(\text{CLKL-NADVL})}$	FSMC_CLK low to FSMC_NADV low	-	2	ns
$t_{d(\text{CLKL-NADVH})}$	FSMC_CLK low to FSMC_NADV high	3	-	ns
$t_{d(\text{CLKL-AV})}$	FSMC_CLK low to FSMC_Ax valid (x=16...25)	-	0	ns
$t_{d(\text{CLKL-AIV})}$	FSMC_CLK low to FSMC_Ax invalid (x=16...25)	2	-	ns
$t_{d(\text{CLKL-NOEL})}$	FSMC_CLK low to FSMC_NOE low	-	0.5	ns
$t_{d(\text{CLKL-NOEH})}$	FSMC_CLK low to FSMC_NOE high	1.5	-	ns
$t_{su(\text{DV-CLKH})}$	FSMC_D[15:0] valid data before FSMC_CLK high	6	-	ns
$t_{h(\text{CLKH-DV})}$	FSMC_D[15:0] valid data after FSMC_CLK high	3	-	ns
$t_{su(\text{NWAIT-CLKH})}$	FSMC_NWAIT valid before FSMC_CLK high	4	-	ns
$t_{h(\text{CLKH-NWAIT})}$	FSMC_NWAIT valid after FSMC_CLK high	0	-	ns

1.  $C_L = 30$  pF.

2. Guaranteed by characterization.

Figure 67. PC Card/CompactFlash controller waveforms for I/O space write access

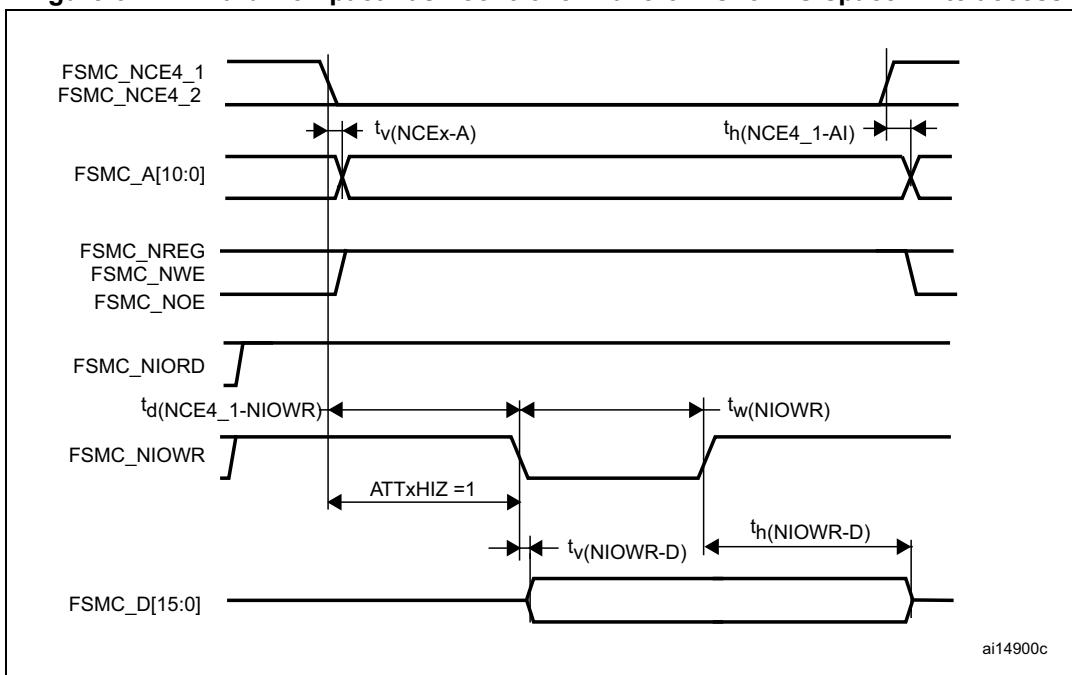


Table 83. Switching characteristics for PC Card/CF read and write cycles in attribute/common space<sup>(1)(2)</sup>

Symbol	Parameter	Min	Max	Unit
$t_{v(NCEx-A)}$	FSMC_Ncex low to FSMC_Ay valid	-	0	ns
$t_{h(NCEx\_AI)}$	FSMC_NCEx high to FSMC_Ax invalid	4	-	ns
$t_{d(NREG-NCEx)}$	FSMC_NCEx low to FSMC_NREG valid	-	3.5	ns
$t_{h(NCEx-NREG)}$	FSMC_NCEx high to FSMC_NREG invalid	$T_{HCLK}+4$	-	ns
$t_{d(NCEx-NWE)}$	FSMC_NCEx low to FSMC_NWE low	-	$5T_{HCLK}+0.5$	ns
$t_{d(NCEx-NOE)}$	FSMC_NCEx low to FSMC_NOE low	-	$5T_{HCLK} +0.5$	ns
$t_w(NOE)$	FSMC_NOE low width	$8T_{HCLK}-1$	$8T_{HCLK}+1$	ns
$t_{d(NOE\_NCEx)}$	FSMC_NOE high to FSMC_NCEx high	$5T_{HCLK}+2.5$	-	ns
$t_{su(D-NOE)}$	FSMC_D[15:0] valid data before FSMC_NOE high	4.5	-	ns
$t_{h(NOE-D)}$	FSMC_NOE high to FSMC_D[15:0] invalid	3	-	ns
$t_w(NWE)$	FSMC_NWE low width	$8T_{HCLK}-0.5$	$8T_{HCLK}+ 3$	ns
$t_{d(NWE\_NCEx)}$	FSMC_NWE high to FSMC_NCEx high	$5T_{HCLK}-1$	-	ns
$t_{d(NCEx-NWE)}$	FSMC_NCEx low to FSMC_NWE low	-	$5T_{HCLK}+ 1$	ns
$t_{v(NWE-D)}$	FSMC_NWE low to FSMC_D[15:0] valid	-	0	ns
$t_h(NWE-D)$	FSMC_NWE high to FSMC_D[15:0] invalid	$8T_{HCLK}-1$	-	ns
$t_d(D-NWE)$	FSMC_D[15:0] valid before FSMC_NWE high	$13T_{HCLK}-1$	-	ns

1.  $C_L = 30$  pF.
2. Guaranteed by characterization.

**Table 86. Switching characteristics for NAND Flash write cycles<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_{w(NWE)}$	FSMC_NWE low width	$4T_{HCLK}-1$	$4T_{HCLK}+3$	ns
$t_{v(NWE-D)}$	FSMC_NWE low to FSMC_D[15-0] valid	-	0	ns
$t_{h(NWE-D)}$	FSMC_NWE high to FSMC_D[15-0] invalid	$3T_{HCLK}-2$	-	ns
$t_{d(D-NWE)}$	FSMC_D[15-0] valid before FSMC_NWE high	$5T_{HCLK}-3$	-	ns
$t_{d(ALE-NWE)}$	FSMC_ALE valid before FSMC_NWE low	-	$3T_{HCLK}$	ns
$t_{h(NWE-ALE)}$	FSMC_NWE high to FSMC_ALE invalid	$3T_{HCLK}-2$	-	ns

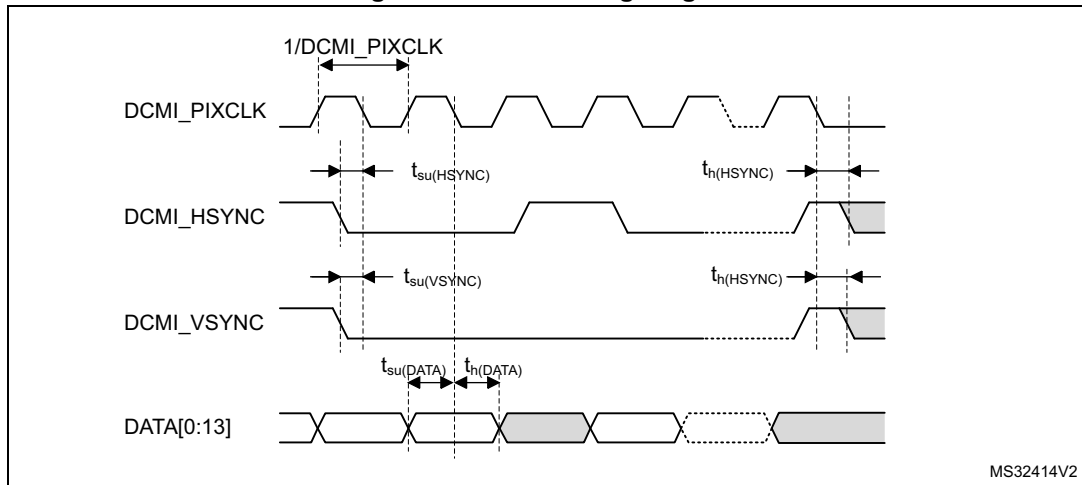
1.  $C_L = 30$  pF.

### 5.3.27 Camera interface (DCMI) timing specifications

Unless otherwise specified, the parameters given in [Table 87](#) for DCMI are derived from tests performed under the ambient temperature,  $f_{HCLK}$  frequency and  $V_{DD}$  supply voltage summarized in [Table 13](#), with the following configuration:

- PCK polarity: falling
- VSYNC and HSYNC polarity: high
- Data format: 14 bits

**Figure 72. DCMI timing diagram**



**Table 87. DCMI characteristics<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
	Frequency ratio DCMI_PIXCLK/ $f_{HCLK}$	-	0.4	
DCMI_PIXCLK	Pixel clock input	-	54	MHz
$D_{pixel}$	Pixel clock input duty cycle	30	70	%



Table 87. DCMI characteristics<sup>(1)</sup> (continued)

Symbol	Parameter	Min	Max	Unit
$t_{su(DATA)}$	Data input setup time	2.5	-	ns
$t_{h(DATA)}$	Data hold time	1	-	
$t_{su(HSYNC)}$ , $t_{su(VSYNC)}$	HSYNC/VSYNC input setup time	2	-	
$t_{h(HSYNC)}$ , $t_{h(VSYNC)}$	HSYNC/VSYNC input hold time	0.5	-	

1. Guaranteed by characterization.

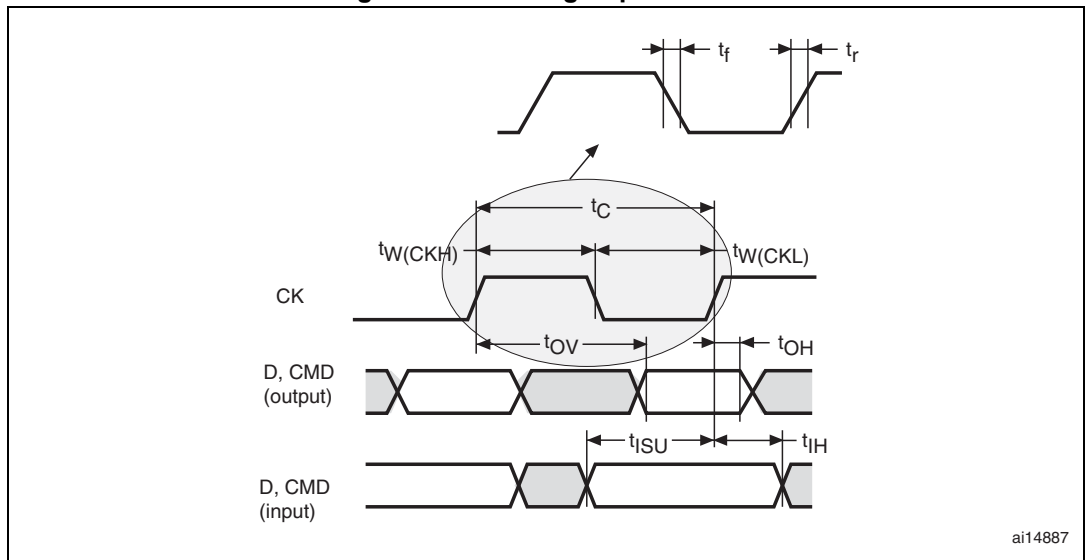
### 5.3.28 SD/SDIO MMC card host interface (SDIO) characteristics

Unless otherwise specified, the parameters given in [Table 88](#) are derived from tests performed under ambient temperature,  $f_{PCLKX}$  frequency and  $V_{DD}$  supply voltage conditions summarized in [Table 14](#) with the following configuration:

- Output speed is set to  $OSPEEDRy[1:0] = 10$
- Capacitive load  $C = 30$  pF
- Measurement points are done at CMOS levels:  $0.5V_{DD}$

Refer to [Section 5.3.16: I/O port characteristics](#) for more details on the input/output characteristics.

Figure 73. SDIO high-speed mode



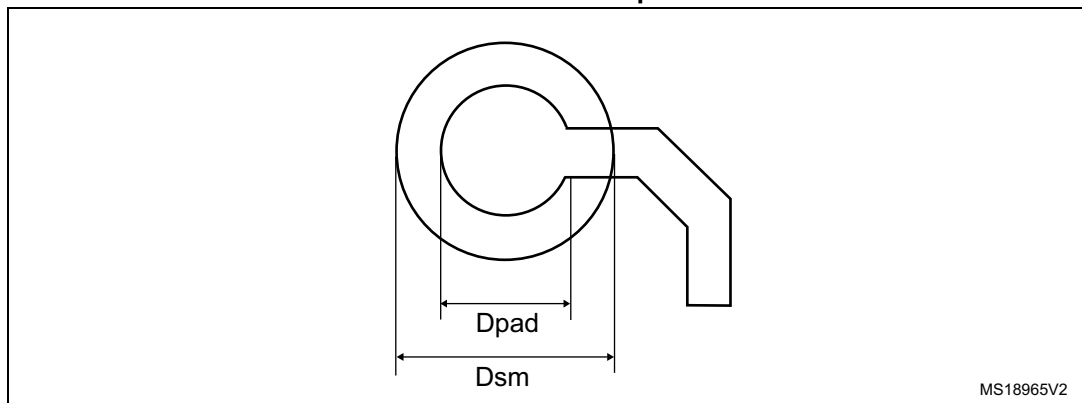
ai14887

**Table 90. WLCSP90 - 4.223 x 3.969 mm, 0.400 mm pitch wafer level chip scale package mechanical data**

Symbol	millimeters			inches <sup>(1)</sup>		
	Min	Typ	Max	Min	Typ	Max
A	0.540	0.570	0.600	0.0213	0.0224	0.0236
A1	-	0.190	-	-	0.0075	-
A2	-	0.380	-	-	0.0150	-
A3 <sup>(2)</sup>	-	0.025	-	-	0.0010	-
b <sup>(3)</sup>	0.240	0.270	0.300	0.0094	0.0106	0.0118
D	4.188	4.223	4.258	0.1649	0.1663	0.1676
E	3.934	3.969	4.004	0.1549	0.1563	0.1576
e	-	0.400	-	-	0.0157	-
e1	-	3.600	-	-	0.1417	-
e2	-	3.200	-	-	0.1260	-
F	-	0.3115	-	-	0.0123	-
G	-	0.3845	-	-	0.0151	-
aaa	-	0.100	-	-	0.0039	-
bbb	-	0.100	-	-	0.0039	-
ccc	-	0.100	-	-	0.0039	-
ddd	-	0.050	-	-	0.0020	-
eee	-	0.050	-	-	0.0020	-

1. Values in inches are converted from mm and rounded to 4 decimal digits.
2. Back side coating.
3. Dimension is measured at the maximum bump diameter parallel to primary datum Z.

**Figure 76. WLCSP90 - 4.223 x 3.969 mm, 0.400 mm pitch wafer level chip scale recommended footprint**



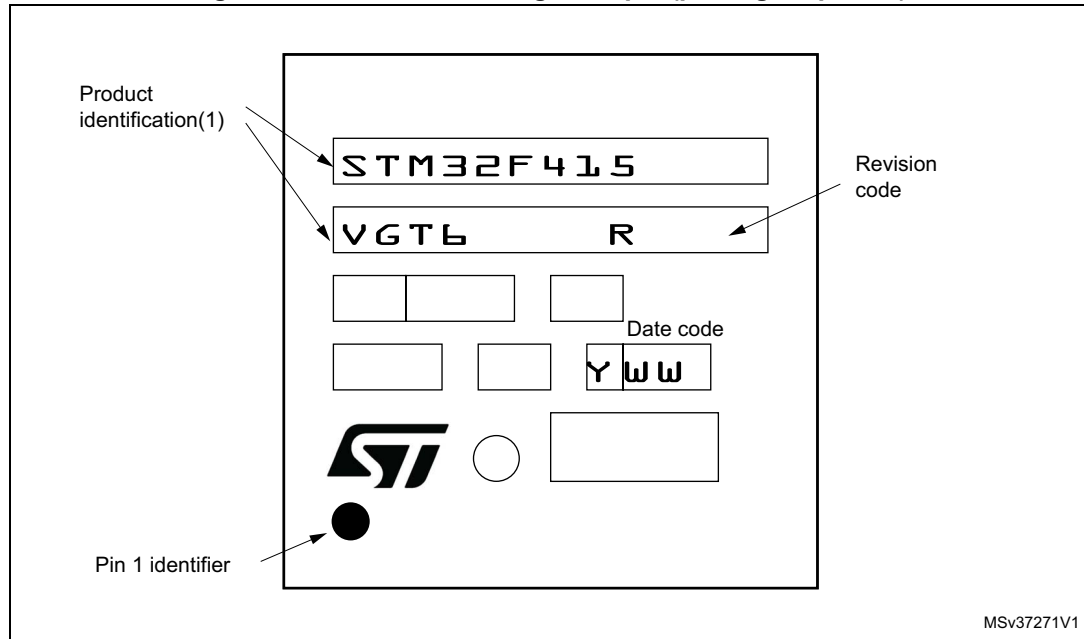


### Device marking for LFP100

The following figure gives an example of topside marking and pin 1 position identifier location.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

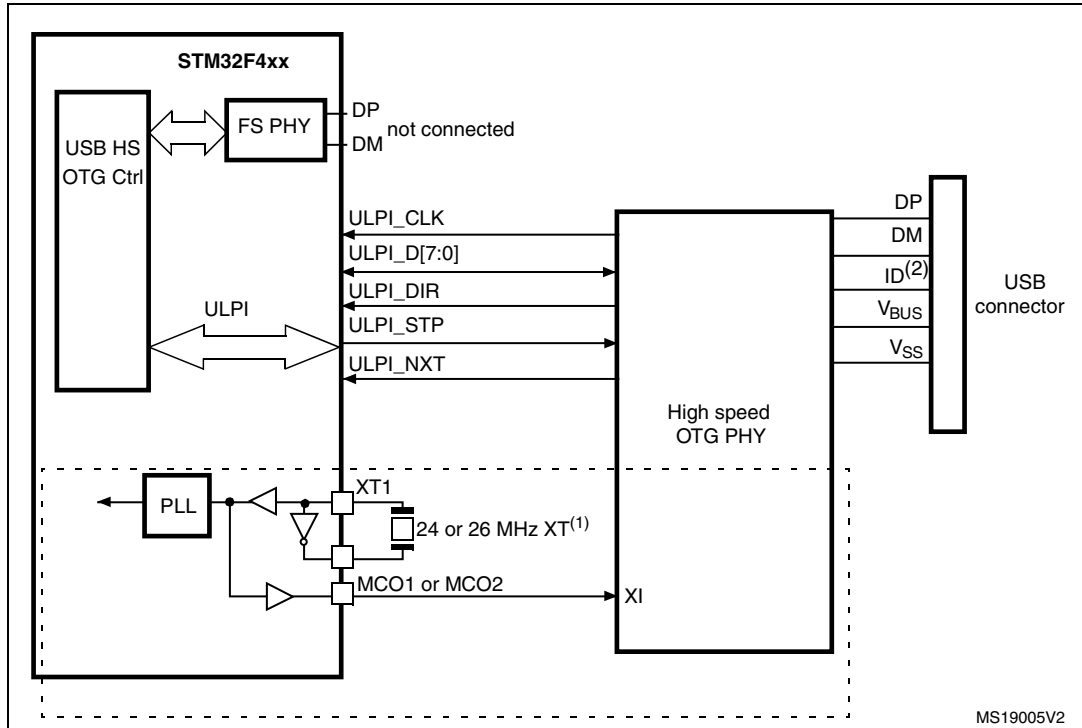
**Figure 83. LQFP100 marking example (package top view)**



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

## A.2 USB OTG high speed (HS) interface solutions

Figure 96. USB controller configured as peripheral, host, or dual-mode and used in high speed mode



1. It is possible to use MCO1 or MCO2 to save a crystal. It is however not mandatory to clock the STM32F41xxx with a 24 or 26 MHz crystal when using USB HS. The above figure only shows an example of a possible connection.
2. The ID pin is required in dual role only.